

10/520 446  
DT15 Re PCT/PTO 06 JAN 2005  
ATENT  
450100-04678

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

Applicants: Takuji HIMENO et al.  
International Application No.: PCT/JP03/08433  
International Filing Date: July 2, 2003  
For: IMAGE DATA PROCESSING APPARATUS AND  
METHOD

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Enclosed are copies of the publications, which were cited in the International  
Search Report of International Application No. PCT/JP03/08433. Also enclosed is a copy of  
Form PTO-1449 and the International Search Report.

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**REMARKS**

Entry of this Information Disclosure Statement and an early examination on the merits are respectfully solicited.

Please charge any additional fees to Deposit Account No. 50-0320.

Respectfully submitted,

FROMMER LAWRENCE & HAUG LLP  
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Enclosures

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Sheet 1 of 1

Based on Form PTO-1449 (3/90)  LIST OF REFERENCES CITED BY APPLICANT (Use several sheets if necessary)	ATTY. DOCKET NO. 450100-04678	SERIAL NO. 10/1520 446 Filed Concurrently Herewith
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U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
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## FOREIGN PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES NO
	AL	JP 11-205734	07/30/99	Japan			
	AM	JP 2000-92448	03/31/00	Japan			
	AN	JP 2001-275077	10/05/01	Japan			
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